



# INTERNATIONAL STANDARD

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**Semiconductor devices –  
Part 16-2: Microwave integrated circuits – Frequency prescalers**

INTERNATIONAL  
ELECTROTECHNICAL  
COMMISSION

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## INTERNATIONAL ELECTROTECHNICAL COMMISSION

### SEMICONDUCTOR DEVICES –

### Part 16-2: Microwave integrated circuits – Frequency prescalers

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International Standard IEC 60747-16-2 has been prepared by subcommittee 47E: Discrete semiconductor devices, of IEC technical committee 47: Semiconductor devices.

This consolidated version of IEC 60747-16-2 consists of the first edition (2001) [documents 47E/160/FDIS and 47E/172/RVD] and its amendment 1 (2007) [documents 47E/338/FDIS and 47E/343/RVD].

The technical content is therefore identical to the base edition and its amendment and has been prepared for user convenience.

It bears the edition number 1.1.

A vertical line in the margin shows where the base publication has been modified by amendment 1.

The committee has decided that the contents of the base publication and its amendments will remain unchanged until the maintenance result date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

## SEMICONDUCTOR DEVICES –

### Part 16-2: Microwave integrated circuits – Frequency prescalers

#### 1 Scope

This part of IEC 60747 provides new measuring methods, terminology and letter symbols, as well as essential ratings and characteristics for integrated circuit microwave frequency prescalers.

#### 2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60617:2001, *Graphical symbols for diagrams*

IEC 60747-1:2006, *Semiconductor devices – Part 1: General*

IEC 60748-2, *Semiconductor devices – Integrated circuits – Part 2: Digital integrated circuits*

IEC 60748-3, *Semiconductor devices. Integrated circuits – Part 3: Analogue integrated circuits*

IEC 60748-4, *Semiconductor devices – Integrated circuits – Part 4: Interface integrated circuits*

IEC 61340-5-1:2007, *Electrostatics – Part 5-1: Protection of electronic devices from electrostatic phenomena - General requirements*

IEC/TR 61340-5-2:2007, *Electrostatics – Part 5-2: Protection of electronic devices from electrostatic phenomena – User guide*